

**Search Notes**

Application/Control No.

10/628,228

Examiner

Alex Liew

Applicant(s)/Patent under  
Reexamination

TAKENAKA, HIDEKI

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/118 (limited to text search)	10/5/2006	AL
382/118 limited to text search	2/7/2007	AL